

<b>Notice of References Cited</b>	Application/Control No. 10/776,610		Applicant(s)/Patent Under Reexamination HABE ET AL.	
	Examiner Brian S. Kwon		Art Unit 1614	Page 1 of 3

#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,296,504	03-1994	Stjerschantz et al.	514/530
*	B	US-5,212,200	05-1993	Ueno et al.	514/530
*	C	US-6,458,836	10-2002	Ueno, Ryuji	514/530
*	D	US-6,596,765	07-2003	Ueno, Ryuji	514/530
*	E	US-5,151,444	09-1992	Ueno et al.	514/530
*	F	US-6,329,426	12-2001	Ueno, Ryuji	514/530
*	G	US-5,405,846	04-1995	Ueno, Ryuji	514/235.8
*	H	US-5,510,383	04-1996	Bishop et al.	514/530
*	I	US-5,397,797	03-1995	Ueno, Ryuji	514/397
*	J	US-5,208,256	05-1993	Ueno, Ryuji	514/530
*	K	US-5,547,968	08-1996	Ueno, Ryuji	514/363
*	L	US-5,432,174	07-1995	Ueno et al.	514/236.2
*	M	US-5,665,773	09-1997	Klimko et al.	514/530

#### FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

#### NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Jack DeRuiter, Principles of Drug Action, Fall 2002, Table in page 5, bottom of page 18 thru page 21.
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

<b>Notice of References Cited</b>	Application/Control No. 10/776,610		Applicant(s)/Patent Under Reexamination HABE ET AL.	
	Examiner Brian S. Kwon		Art Unit 1614	Page 2 of 3

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,889,052	03-1999	Klimko et al.	514/530
*	B	US-5,627,209	05-1997	DeSantis et al.	514/530
*	C	US-6,291,521	09-2001	Ueno, Ryuji	514/530
*	D	US-6,184,250	02-2001	Klimko et al.	514/530
*	E	US-6,344,478	02-2002	Dean et al.	514/530
*	F	US-6,417,228	07-2002	Klimko, Peter G.	514/530
*	G	US-6,723,748	04-2004	Klimko et al.	514/530
*	H	US-6,225,348	05-2001	Paulsen, Alfred W.	514/530
*	I	US-6,197,821	03-2001	Ueno, Ryuji	514/573
*	J	US-5,807,892	09-1998	Klimko et al.	514/530
*	K	US-6,169,111	01-2001	Zinke et al.	514/530
*	L	US-6,342,524	01-2002	Hellberg et al.	514/530
*	M	US-5,422,369	06-1995	Stjernschantz et al.	514/530

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

<b>Notice of References Cited</b>	Application/Control No. 10/776,610	Applicant(s)/Patent Under Reexamination HABE ET AL.	
	Examiner Brian S. Kwon	Art Unit 1614	Page 3 of 3

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,422,368	06-1995	Stjernschantz et al.	514/530
*	B	US-5,296,504	03-1994	Stjernschantz et al.	514/530
*	C	US-5,849,791	12-1998	Stjernschantz et al.	514/530
*	D	US-6,417,230	07-2002	Stjernschantz et al.	514/530
*	E	US-6,429,226	08-2002	Stjernschantz et al.	514/530
*	F	US-6,025,392	02-2000	Selliah et al.	514/473
*	G	US-6,160,013	12-2000	Selliah, Robert D.	514/530
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.